

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L DEKRA 16.0002 Issue No.: 4 Status: Current

Supersedes: IECQ-L DEKRA 16.0002 Issue 3 Issue Date: 2019/08/19 Org Issue: 2016/08/17

CB Reference No.: DEKRA-T5A-001 Expiration: 2022/08/16

Integrated Service Technology, Inc.

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The organization, facilities and procedures have been assessed and found to comply with the applicable requirements for Independent Testing Laboratory organization approval, in support of the IECQ system, which is in accordance with the Basic Rules IECQ 01 and Rules of Procedure IECQ 03-6 "Independent Testing Laboratory Assessment Program Requirements" of the IEC Quality Assessment System for Electronic Components (IECQ) and applicable requirements of ISO/IEC 17025:2017 for the testing of electronic components under the IECQ.

Scope:

Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

See attached Schedule of Scope

-- Attached Schedule: IECQ-L DEKRA 16.0002-S Rev3.pdf --

Approved by Certification Body (CB): DEKRA Certification B.V.

Meander 1051

Arnhem

Netherlands

Authorized person:

Ted Gaertner







The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.

This Certificate of Conformity may be suspended or withdrawn in accordance with the Rules of Procedure of the IECQ System and its Schemes.

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Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L DEKRA 16.0002
CB Certificate No.: DEKRA-T5A-001

Schedule Number: IECQ-L DEKRA 16.0002-S Rev No.: 3 Rev. Date: 2019/08/19 Page 1 of 1

1. Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

Description test	Standard	Remarks
Consumer / Commercial / Industrial (JESD 47) and Automotive / Military accelerated environment reliability stress tests. (Including: Pre-condition / MSL / Accelerated Temperature-Humidity test / Unbiased Autoclave /Liquid to liquid thermal shock/Air to air thermal shock/ Unbiased HAST/biased HAST/Temperature-Humidity with bias test / Temperature Cycling test / Power and temperature cycling / High and low Temperature storage test / IOL/ Salt)	J-STD-020, JESD22- A101/A102/A103/A104/A105/ A106/A107/A110/A113/A118/A119; IEC- 60068-2-1/2/3/14/38/52/, MIL-STD-202/750/810/883, JESD JEP001; EIA-364-32, EIAJ ED-4701, AEC-Q200-004; AEC-Q005/Q006, JESD22-A105	Or customer specified test
Consumer/ Commercial / Industrial (JESD 47) and Automotive / Military accelerated lifetime simulation tests. (Including: Temperature, Bias, and Operating Life test / early life failure rate / Endurance and Data retention test / Short circuit / Low Temperature Operating Life / Miscellaneous test)	JESD22-A101/A108/A117, MIL-STD-202/750/810/883, AEC-Q100-005/006/008/012, AEC-Q101-004/006, Customer standards	Or customer specified test
Consumer / Commercial / Industrial (JESD 47) and Automotive / Military 2nd level integration platform service. (Including: Pre-SMT/SMT / Temperature Cycling test / Temperature-Humidity test / Drop / Shock / Bending(9point) / Pull and Push test / Solderability / Press / Shear / Hardness / RCA / Durability / Peeling / Terminal Strength / Resistance to Solvents / Resistance to Solder Heat / Hermeticity / Package Warpage Measurement of Surface-Mount Integrated Circuits at Elevated Temperature / Printed Wiring Board Strain Gage Test / Mechanical Compressive Static Stress Test	IPC-7525/9701/9702/9704/9707/9708/A-610, JESD22-A101/A104/A106/A109/A111/B100/B102/B103/B104/B105/B106/B1 07/B108/B110/B111/B112/B113/B115/B116/B117/B119; EIAJ ED-4702, EIA-364-09/13; AEC-Q100-001/010; AEC-Q101-003, AEC-Q200-003/005/006; MIL-STD-202/750/810/883, J-STD-002/003; ASTM D3363, ASTM F2357; SEMI G86-0303, IEC 60068-2-21; IEC-60068-2-14; IPC-TM-650,	Or customer specified test
Electrical Analysis, Sample Preparation (Decap, X-section, etc), NDE (Non-destructive Engineering), Physical & Chemical Analysis (Including Hazardous Substances) and IC package.	IPC-TM-650, IPC-610, J-STD-020, JESD201, EIA-469, IEC62321, EN14582,	Or customer specified test

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